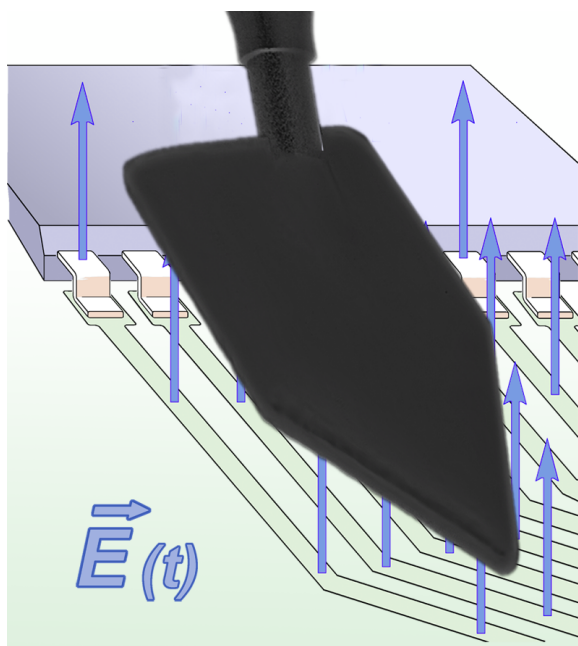


RF-E 02

电场探头 (30MHz-3GHz)

LANGER
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Short description

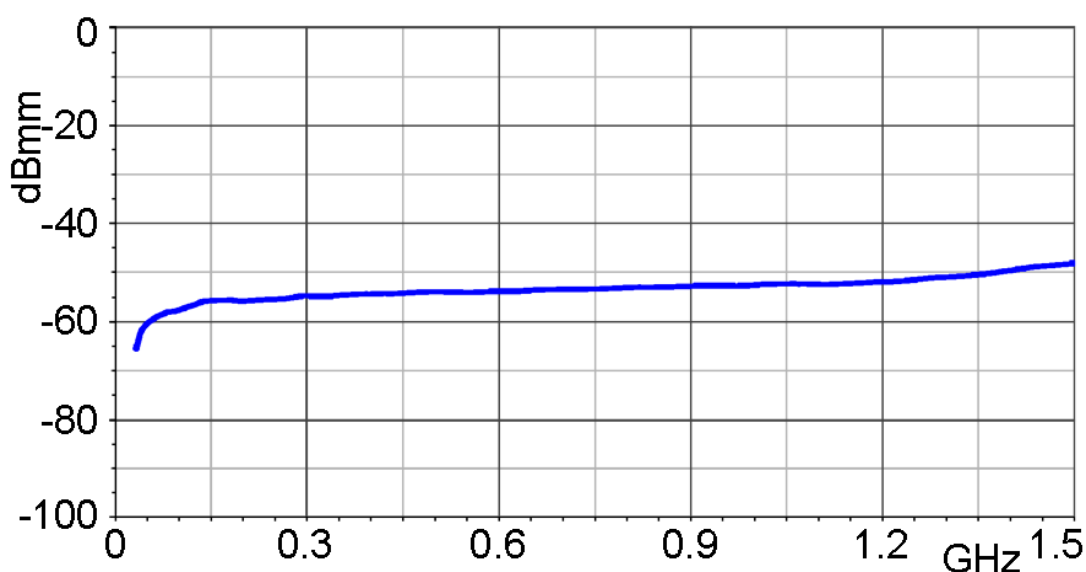
RF-E 02型近场探头用于测量总线结构、较大的元器件或者供电表面产生的耦合电场。探头下方的电极面积大约是2 cm x 5 cm。该探头用于在距离模块1cm到2 cm的位置检测。

The RF-E 02 is a passive near-field probe. In principle it has the same structure as the RF-E 05 and RF-E 10 probes. When measuring, the bottom surface of the probe head is positioned close to the measured object. This allows the E-field emitted by an assembly to be detected. To achieve a higher resolution, only the tip of the probe head should be held toward the measured object. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

频率范围	30 MHz - 1.5 GHz
探头尺寸	$\approx (23 \times 53)$ mm
输出接口	SMB, male, jack

频率特性 [dB μ V] / [dB μ V/mm]

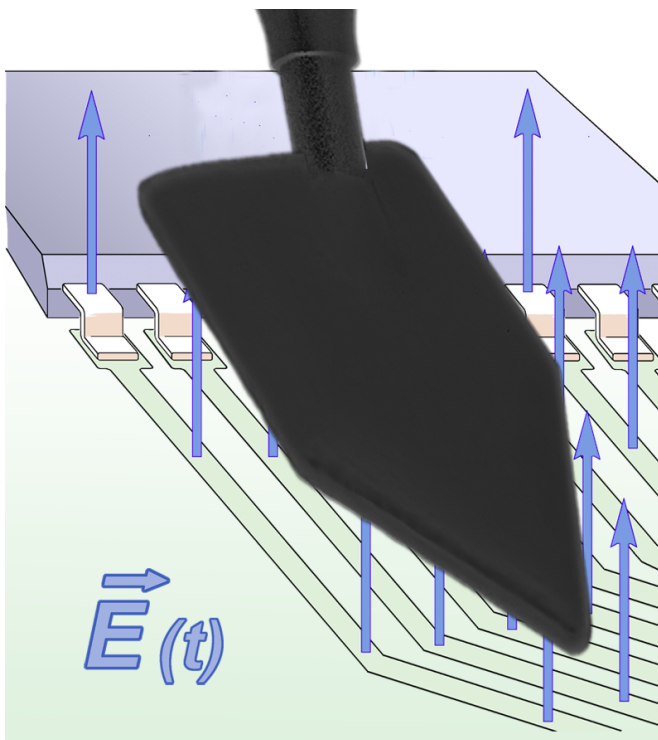
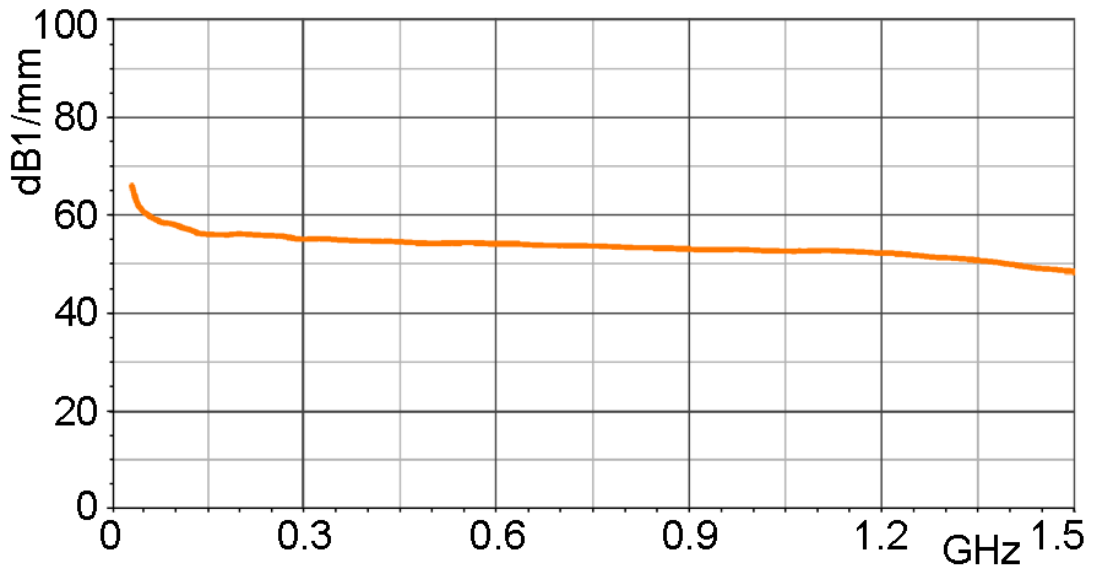


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电场校正曲线 [dB μ V/mm] / [dB μ V]



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Probe head

